

NANOSCALE RESEARCH FACILITY
Room No. 116, BLOCK-VI, IIT DELHI
Hauz Khas, New Delhi - 110016
Tel: 011 265 96784

Request Form

AGM, XRD, SEM, AFM, DLS, HPLC, Optical Profiler, Stylus surface profiler, Raman

stress measurement, Photo Electrochemical Work station, Scanning Electrochemical Microscope,

Zeta/Autotitrator/ Xenon Lamp, Optical Table and Optical component, GCMS \ UV FTIR PL

1.Name of the Requestor: _____

2.Designation: _____

3.Contact details:
Mobile: _____
Lab landline No _____
E-mail: _____

4.Dept./Centre/Lab/Institution: _____

5.Equipment required: _____

6.Brief description of the samples:
(DLS) _____

7.No. of samples: _____

8.Brief description of the required
characterization: (specifications if
any)

9.Description of the samples (RI):

10.Description of the solvent (RI/
Viscosity):

11.Number of sample:

12.Duration of measurement: _____

13.Type of cell (DLS/ Zeta) :

14.Name of the Guide/Supervisor:

15.Member of NRF:

Yes/No

16.Remarks (if any):

Date:

Signature of the Researcher

Signature of the Guide/Supervisor

FOR INTERNAL OFFICE USE ONLY

1. Name of the Faculty In-charge: _____

2. Signature of the Faculty In-charge: _____

3. Proposed date and time of measurement: _____

4. Actual date of measurement: _____

5. Name of the TA/Operator: _____

6. Signature of the TA/Operator: _____

Imp _ All users are requested to note the following:

- a) Maximum 2 samples (XRD) are allowed at a time. The data would be provided in CDs only, so kindly bring your own blank CDs.
- b) Users will be informed about their turn through email/internal phone.
- c) If the results are used in a publication, the facility at NRF and funding support from DeitY should be acknowledged.